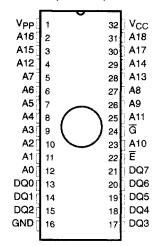
SGMS046B - NOVEMBER 1992 - REVISED SEPTEMBER 1997

- Organization . . . 524288 by 8 Bits
- Single 5-V Power Supply
- Industry Standard 32-Pin Dual-In-line Package
- All Inputs/Outputs Fully TTL Compatible
- Static Operation (No Clocks, No Refresh)
- Max Access/Min Cycle Time

V _{CC} ± 10%	
'27C040-10	100 ns
'27C040-12	120 ns
'27C040-15	150 ns

- 8-Bit Output For Use in Microprocessor-Based Systems
- Power-Saving CMOS Technology
- 3-State Output Buffers
- 400-mV DC Assured Noise Immunity With Standard TTL Loads
- Latchup Immunity of 250 mA on All Input and Output Pins
- No Pullup Resistors Required
- Low Power Dissipation (V_{CC} = 5.5 V)
 - Active . . . 385 mW Worst Case
 - Standby . . . 0.55 mW Worst Case (CMOS-Input Levels)
- Military Operating Temperature Range
 55°C to 125°C

J PACKAGE (TOP VIEW)



PIN NOMENCLATURE						
Address Inputs						
Inputs (programming)/Outputs						
Chip Enable						
Output Enable						
Ground						
5-V Supply						
13-V Power Supply†						

[†] Only in program mode

description

The SMJ27C040 is a set of 4194304-bit, ultraviolet-light erasable, electrically programmable read-only memories (EPROMs).

These devices are fabricated using CMOS technology for high speed and simple interface with MOS and bipolar circuits. All inputs (including program data inputs) can be driven by Series 54 TTL circuits. Each output can drive one Series 54. TTL circuit without external resistors. The data outputs are 3-state for connecting multiple devices to a common bus.

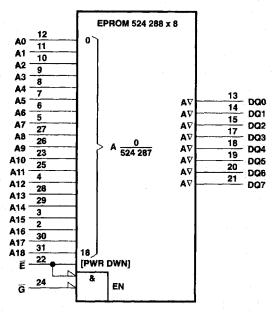
The SMJ27C040 is offered in a 32-pin 600-mil dual-in-line ceramic package (J suffix) rated for operation from – 55°C to 125°C.

Since this EPROM operates from a single 5-V supply (in the read mode), it is ideal for use in microprocessor-based systems. One other (13-V) supply is needed for programming. All programming signals are TTL level. For programming outside the system, existing EPROM programmers can be used.



SGMS0468 - NOVEMBER 1992 - REVISED SEPTEMBER 1997

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the J package.

operation

The seven modes of operation are listed in Table 1. The read mode requires a single 5-V supply. All inputs are TTL level except for V_{PP} during programming (13 V), and V_{H} (12 V)§ on A9 for signature mode.

Table 1. Operation Modes

		FUNCTION						
	Ē	Ğ	Vpp	Vcc	A9	A0	DQ0-DQ7	
Read	VIL	VIL	VCC	Vcc	Х	Х	Data Out	
Output Disable	VIL	VIΗ	Vcc	Vcc	Х	X	Hi-Z	
Standby	VIH	Х	VCC	VCC	Х	X	Hi-Z	
Programming	VIL	ViH	Vpp	Vcc	Х	Х	Data In	
Program Inhibit	VIH	VjΗ	Vpp	Vcc	Х	Х	Hi-Z	
Verify	ViH	V _{IL}	Vpp	Vcc	Х	Х	Data Out	
Cinnatura Mada	V.,	V.,	V	Vaa	t	VIL	MFG Code 97	
Signature Mode	VIL	VIL VCC	Vcc	VIH‡	VIH	Device Code 50		

X can be VIL or VIH.



⁹ VH = 12 V ± 0.5 V

SGMS046B - NOVEMBER 1992 - REVISED SEPTEMBER 1997

read/output disable

When the outputs of two or more SMJ27C040s are connected in parallel on the same bus, the output of any particular device in the circuit can be read with no interference from competing outputs of the other devices. To read the output of a single device, a low level signal is applied to the \overline{E} and \overline{G} pins. All other devices in the circuit should have their outputs disabled by applying a high level signal to one of these pins. Output data is accessed at pins Q0-Q7.

latchup immunity

Latchup immunity on the SMJ27C040 is a minimum of 250 mA on all inputs and outputs. This feature provides latchup immunity beyond any potential transients at the P.C. board level when the EPROM is interfaced to industry standard TTL or MOS logic devices. The input/output layout approach controls latchup without compromising performance or packing density.

For more information see application report SMLA001, "Design Considerations; Latchup Immunity of the HVCMOS EPROM Family", available through TI Sales Offices.

power down

Active I_{CC} supply current can be reduced from 70 mA to 1 mA for a high TTL input on \overline{E} and to 100 μ A for a high CMOS input on \overline{E} . In this mode all outputs are in the high-impedance state.

erasure

Before programming, the SMJ27C040 EPROM is erased by exposing the chip through the transparent lid to a high intensity ultraviolet-light (wavelength 2537 Å). The recommended minimum exposure dose (UV intensity × exposure time) is 15-W·s/cm². A typical 12-mW/cm², filterless UV lamp erases the device in 21 minutes. The lamp should be located about 2.5 cm above the chip during erasure. After erasure, all bits are in the high state. It should be noted that normal ambient light contains the correct wavelength for erasure. Therefore, when using the SMJ27C040, the window should be covered with an opaque label. After erasure (all bits in logic high state), logic lows are programmed into the desired locations. A programmed low can be erased only by ultraviolet light.

SNAP! Pulse programming

The SMJ27C040 and TMS27PC040 are programmed by using the SNAP! Pulse programming algorithm. The programming sequence is shown in the SNAP! Pulse programming flow chart (Figure 1).

The initial setup is $V_{PP} = 13 \text{ V}$, $V_{CC} = 6.5 \text{ V}$, $\overline{E} = V_{IH}$, and $\overline{G} = V_{IH}$. Once the initial location is selected, the data is presented in parallel (eight bits) on pins DQ1 through DQ8. Once addresses and data are stable, the programming mode is achieved when \overline{E} is pulsed low (V_{IL}) with a pulse duration of $t_{w(PGM)}$. Every location is programmed only once before going to interactive mode.

In the interactive mode, the word is verified at $V_{PP}=13~V,~V_{CC}=6.5~V,~\overline{E}=V_{IH},~$ and $\overline{G}=V_{IL}.$ If the correct data is not read, the programming is performed by pulling \overline{G} high, then \overline{E} low with a pulse duration of $t_{w(PGM)}$. This sequence of verification and programming is performed up to a maximum of 10 times. When the device is fully programmed, all bytes are verified with $V_{CC}=V_{PP}=5~V\pm10\%.$

program inhibit

Programming can be inhibited by maintaining high level inputs on the E and G pins.



SGMS0468 - NOVEMBER 1992 - REVISED BEPTEMBER 1997

program verify

Programmed bits can be verified with $V_{PP} = 13 \text{ V}$ when $\overline{G} = V_{IL}$, and $\overline{E} = V_{IH}$.

The signature mode provides access to a binary code identifying the manufacturer and type. This mode is activated when A9 (pin 26) is forced to 12 V. Two identifier bytes are accessed by toggling A0. All other addresses must be held low. The signature code for the SMJ27C040 is 9750. A0 low selects the manufacturer's code 97 (Hex), and A0 high selects the device code 50 (Hex), as shown in Table 2.

Table 2. Signature Modes

	PINS									
IDENTIFIER†	A0	DQ7	DQ6	DQ5	DQ4	DQ3	DQ2	DQ1	DQ0	HEX
MANUFACTURER CODE	VIL	1	G .	0	1	0	1	1	1	97
DEVICE CODE	ViH	0	1	0	1	0	0	0	0	50

TE = G = VIL, A1 - A8 = VIL, A9 = VH, A10-A18 = VIL, VPP = VCC.

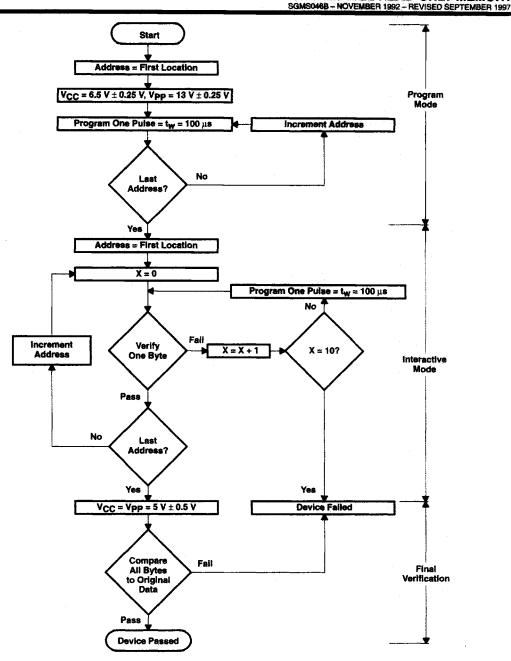


Figure 1. SNAP! Pulse Programming Flow Chart



SGMS046B - NOVEMBER 1992 - REVISED SEPTEMBER 1997

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} (see Note 1)	0.6 V to 7 V
Supply voltage range, Vpp (see Note 1)	0.6 V to 14 V
Input voltage range (see Note 1), All inputs except A9	0.6 V to 6.5 V
A9	
Output voltage range, with respect to V _{SS} (see Note 1)0	.6 V to V _{CC} + 1 V
Minimum operating free-air temperature	– 55°C
Maximum operating case temperature	125°C
Storage temperature range	-65°C to 125°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. NOTE 1: All voltage values are with respect to GND.

recommended operating conditions

				MIN	TYP	MAX	UNIT
V	Commissionia	Read mode (see Note 2)	Read mode (see Note 2)			5.5	٧
VCC	Supply voltage	SNAP! Pulse programming	algorithm	6.25	6.5	6.75	٧
Vpp Supply voltage	Complexically	Read mode (see Note 3)		V _C C - 0.6		V _{CC} + 0.6	٧
	Supply voltage	SNAP! Pulse programming	12.75	13	13.25	ν	
			TTL	2		VCC+0.5	1,7
VIH.	High-level input voltage		CMOS	V _{CC} - 0.2		V _{CC} +0.5	V
	Law taval innut rate	TTL		- 0.5		0.8	.,
VIL	Low-level input voltage CMOS		- 0.5		0.2	٧	
TA	Operating free-air temperature			- 55			°C
тс	Operating case temperature					125	°C

NOTES: 2. VCC must be applied before or at the same time as Vpp and removed after or at the same time as Vpp. The device must not be inserted into or removed from the board when Vpp or VCC is applied.

3. Vpp can be connected to VCC directly (except in the program mode). VCC supply current in this case would be ICC + Ipp. During programming, Vpp must be maintained at 13 V \pm 0.25 V.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature

	PARAMETER		TEST CONDITIONS	MIN MAX	UNIT
VOH	High-level output voltage		I _{OH} = - 400 µA	2.4	٧.
VOL	Low-level output voltage		IOL = 2.1 mA	0.4	٧
l _j	input current (leakage)		V _I = 0 V to 5.5 V	±1	μА
lo	Output current (leakage)		VO = 0 V to VCC	±1	μА
IPP1	Vpp supply current		Vpp = V _{CC} = 5.5 V	10	μΑ
IPP2	Vpp supply current (during program pu	ulse) (see Note 4)	Vpp = 12.75 V, TA - 25°C	50	mΑ
1	Mary and a support (about the sale)	TTL-Input level	$V_{CC} = 5.5 \text{ V}.$ $\overline{E} = V_{IH}$	1	mA
ICC1	V _{CC} supply current (standby)	CMOS-Input level	V _{CC} = 5.5 V, E = V _{CC}	100	μА
ICC2	VCC supply current (active)		E = V _{IL} , V _{CC} = 5.5 V t _{cycle} = minimum cycle time, outputs open (see Note 5)	50	mA

NOTES: 4. This parameter is only sampled and not 100% tested.

5. Minimum cycle time = maximum access time.



capacitance over recommended ranges of supply voltage and operating free-air temperature, $f = 1 \text{ MHz} (V_{CC} = V_{PP} = 5 \text{ V} \pm 0.5 \text{ V})^{\dagger}$

	PARAMETER	TEST CONDITIONS	MIN	TYP‡	MAX	UNIT
Ci	Input capacitance	V _I = 0 V		4	8	ρF
Co	Output capacitance	V _O = 0 V		8	12	pF

[†] Capacitance is sampled only at initial design and after any major change.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (see Notes 7 and 8)

	PARAMETER	TEST CONDITIONS			'27C040-12		'27C040-15		126107
	FANAMETEN		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
ta(A)	Access time from address			100		120		150	ns
ta(E)	Access time from chip enable		<u> </u>	100		120		150	ns
ten(G)	Output enable time from G	(see Figure 2)		50		50	-	50	ns
^t dis	Output disable time from \overline{G} or \overline{E} , whichever occurs first (see Note 8)	Input $t_r \le 20 \text{ ns}$ Input $t_f \le 20 \text{ ns}$	0	50	0	50	0	50	ns
t _V (A)	Output data valid time after change of address, \overline{E} , or \overline{G} , whichever occurs first (see Note 8)		0		0		0		ns

NOTES: 6. For all switching characteristics the input pulse levels are 0.4 V to 2.4 V. Timing measurements are made at 2 V for logic high and 0.8 V for logic low. (Figure 2)

7. Common test conditions apply for tdis except during programming. 8. Value calculated from 0.5-V delta to measured output level. This parameter is only sampled and not 100% tested.

switching characteristics for programming: $V_{CC} = 6.5 \text{ V}$ and $V_{PP} = 13 \text{ V}$ (SNAP! Pulse), $T_A = 25^{\circ}\text{C}$

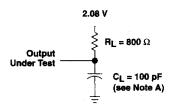
	PARAMETER	MIN	MAX	UNIT
^t dis(G)	Output disable time from G	0	100	ns
ten(G)	Output enable time from \overline{G}		150	ns

timing requirements for programming

			MIN	TYP	MAX	UNIT
^t h(A)	Hold time, address		0			μs
th(D)	Hold time, data		2			μs
tw(PGM)	Pulse duration, program	SNAP! Pulse programming algorithm	95	100	105	μs
t _{su(A)}	Setup time, address		2			μs
tsu(E)	Setup time, E		2			μs
tsu(G)	Setup time, G		2			μs
tsu(D)	Setup time, data		2			μs
t _{su(VPP)}	Setup time, Vpp		2			μs
tsu(VCC)	Setup time, V _{CC}		2			μs

[‡] Ali typical values are at T_A = 25°C and nominal voltages.

PARAMETER MEASUREMENT INFORMATION



NOTE A: CL includes probe and fixture capacitance.

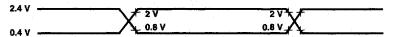


Figure 2. Output Load Circuit and Input/Output Wave Forms

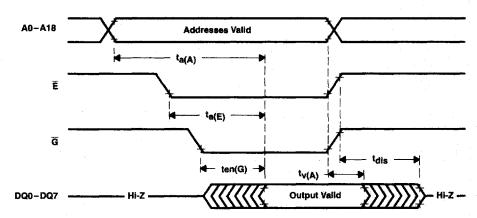
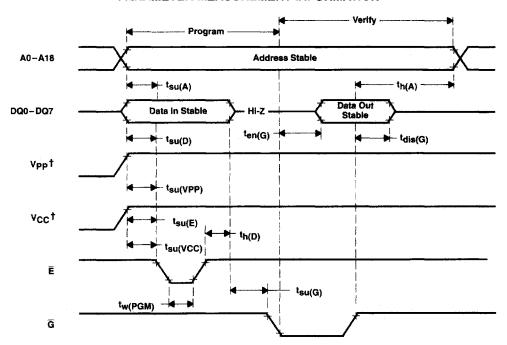


Figure 3. Read-Cycle Timing

PARAMETER MEASUREMENT INFORMATION



† 13-V Vpp and 6.5-V VCC for SNAP! Pulse programming.

Figure 4. Program-Cycle Timing (SNAP! Pulse Programming)